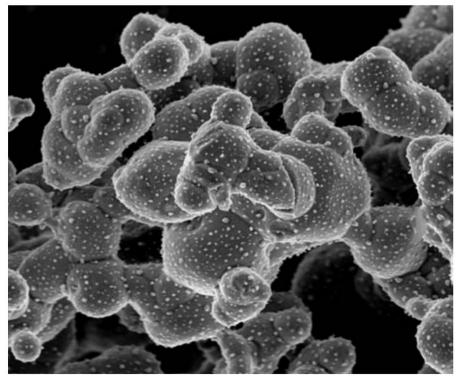


Secondary electron image (a) shows the presence of contamination due to imaging in high vacuum (large dark rectangle). As shown in (b), in VPESEM mode, it can remove the presence of contamination in (a) (small bright rectangle).



Silver oxide ceramic imaged using water vapor with pressure p = 40 Pa (0.3 torr). Primary beam energy E0 = 5 keV. Horizontal field width = 11  $\mu m$ .